

Searches for type-III (and type-II) seesaw heavy leptons with the ATLAS detector

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Outline

- Past ATLAS analyses on type-II and type-III seesaw
- Overview of latest type-III seesaw analyses with 2-, 3- and 4-lepton final states
 - Analysis strategy and approach
 - (type-II covered in Blaž Leban's talk tomorrow)
- Current latest results
- Status of new ongoing analyses for type-II and type-III seesaw
 - **Planned improvements to increase sensitivity**



Past ATLAS type-II and type-III seesaw analyses

Type-II

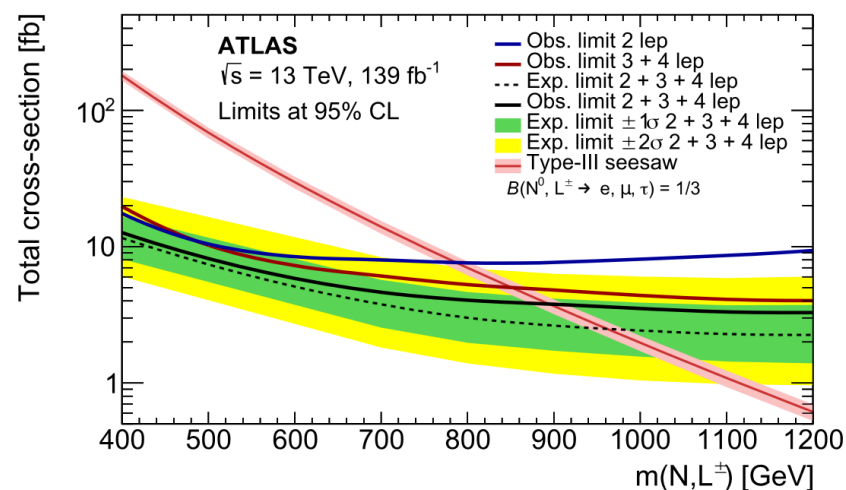
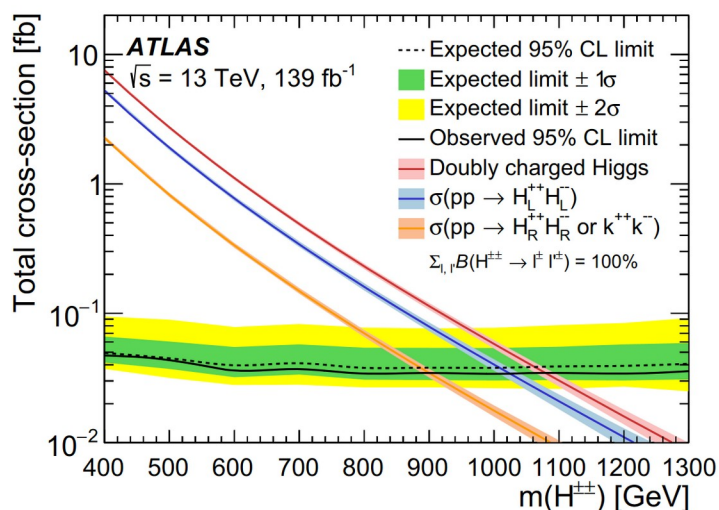
- Run 2 (140 fb⁻¹, √s = 13 TeV)
 - 2015-2016 data only – M ≥ 870 GeV
Eur. Phys. J. C 78, 199 (2018)
 - H^{±±} → W[±]W[±] – M > 350 GeV
J. High Energy Phys. 2021 (6), 146
 - H^{±±} → ℓ[±]ℓ[±] – M > 1080 GeV
Eur. Phys. J. C 83, 605 (2023)

Covered in talk by
Blaž Leban

Type-III

- Run 1 (20.3 fb⁻¹, √s = 8 TeV)
 - 2-lepton final state – M > 335 GeV
Phys. Rev. D 92, 032001 (2015)
 - 3-lepton final state – M > 400 GeV
J. High Energy Phys. 2015 (9), 108
- Run 2 (140 fb⁻¹, √s = 13 TeV)
 - 2-lepton final state – M > 790 GeV
Eur. Phys. J. C 81, 218 (2021)
 - Combined 2 + 3,4-lepton final state – M > 910 GeV
Eur. Phys. J. C 82, 988 (2022)

Covered in this talk



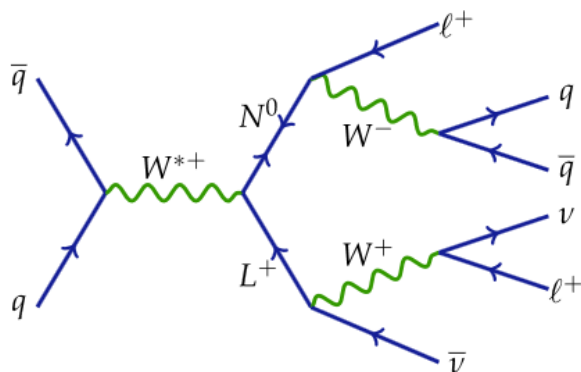


Latest type-III seesaw analyses at ATLAS

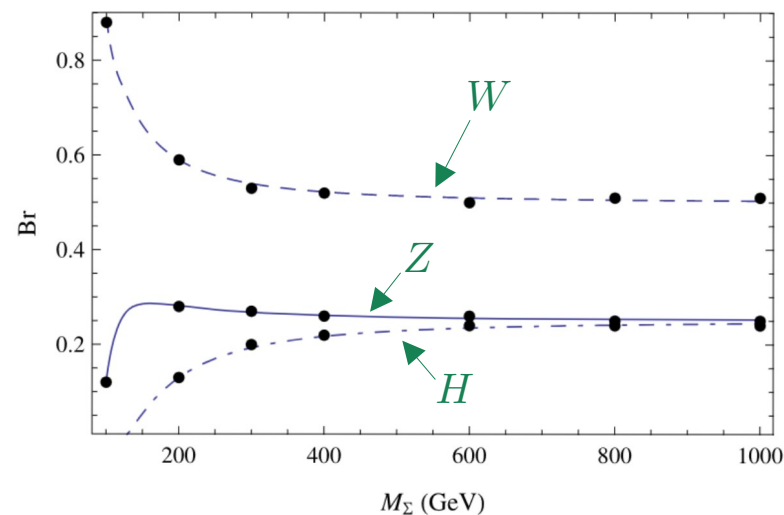
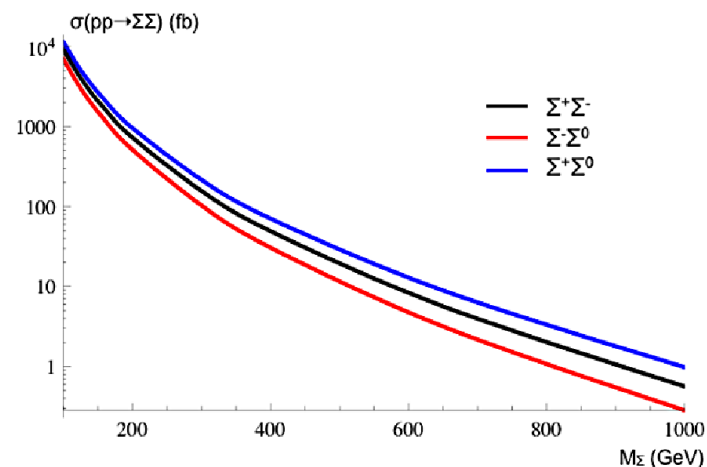
- Simplified model with **single heavy triplet**
- Predominantly associated and pair production via gauge interaction (single triplet production suppressed)
- Set **equal mixing angles** to get equal branching ratios into SM leptons

$$V_e = V_\mu = V_\tau$$

- Largest decay branching ratio into W
- Consider final states with ...
 - At least two leptons
 - Light leptons (e, μ) only – leptonic tau decays included
- Cut-based approach → Kinematic cuts to maximize signal significance
 - Define dedicated signal regions (SR) and control regions (CR)



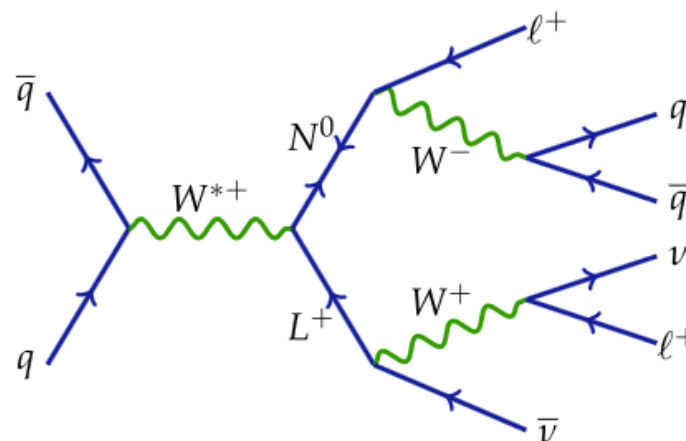
$$\text{Br}_\ell \propto \frac{|V_\ell|^2}{\sum_i |V_i|^2}$$





Type-III seesaw analysis approach

- **Event selection**
 - Dilepton ($ee, e\mu, \mu\mu$) triggers without isolation requirement – p_T thresholds all below 24 GeV
- **Baseline object definition (for counting and data-driven background estimation)**
 - **Electrons and muons**
 - Requirements on identification and isolation
 - $p_T > 10$ GeV
 - $|\eta| < 2.5$
 - **Jets**
 - $p_T > 20$ GeV
 - $|\eta| < 2.5$
 - b-tagging (for b-jet veto)
 - Missing transverse energy (**MET**)
- Apply corrections to MC correct mismodelings of identification, isolation and trigger efficiencies



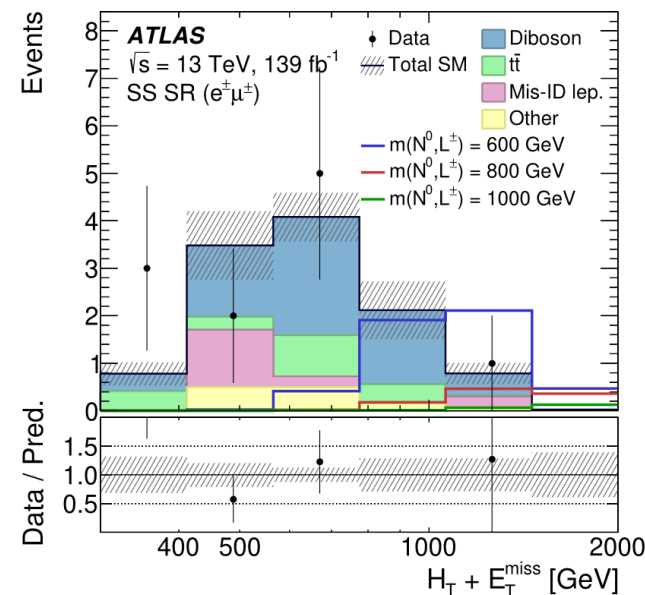
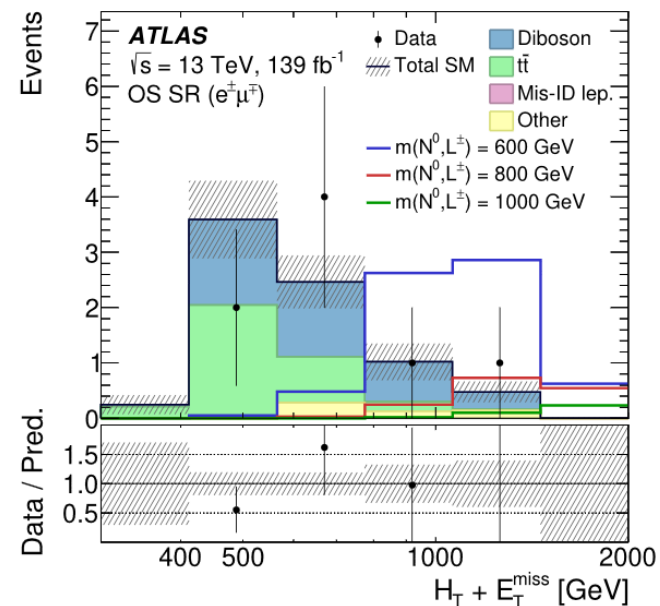
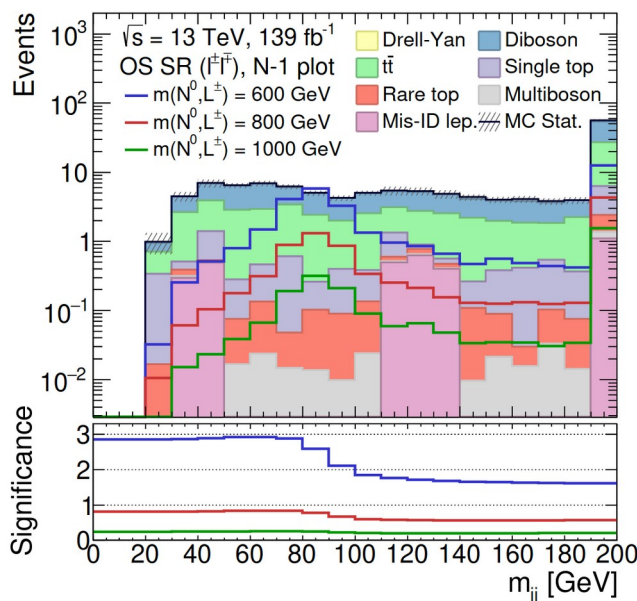
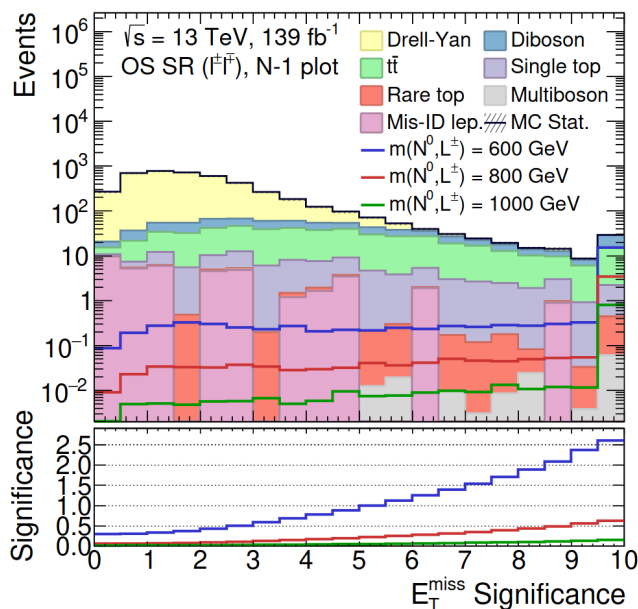


Signal region selection

- p_T cut increased to 40 GeV for leading leptons
- Important cuts on $\text{Sig}(E_T^{\text{miss}})$ at 5 or more and $H_T + E_T^{\text{miss}} > 300$ GeV
- **SRs are divided by lepton multiplicity in the final state**

2 leptons

- Separate same sign (SS) and opposite sign (OS)
- At least two jets – b-jet veto
- Main cuts on dilepton mass above Z peak, dijet mass kept around W peak





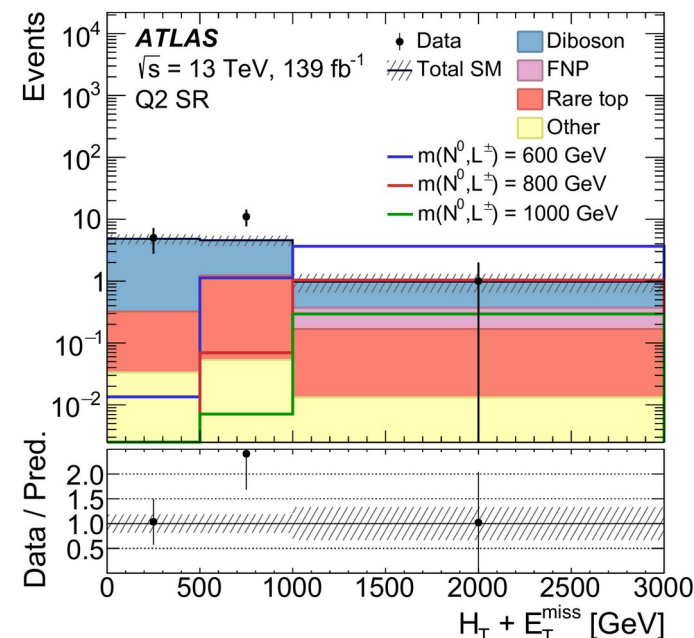
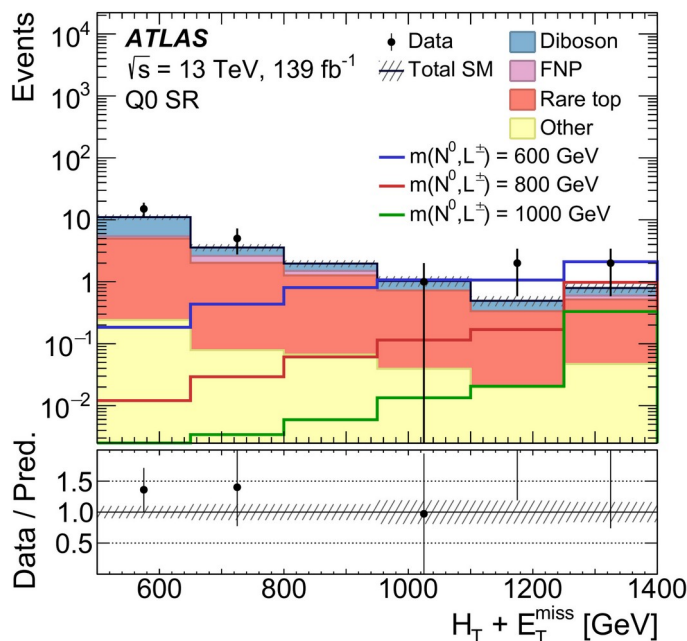
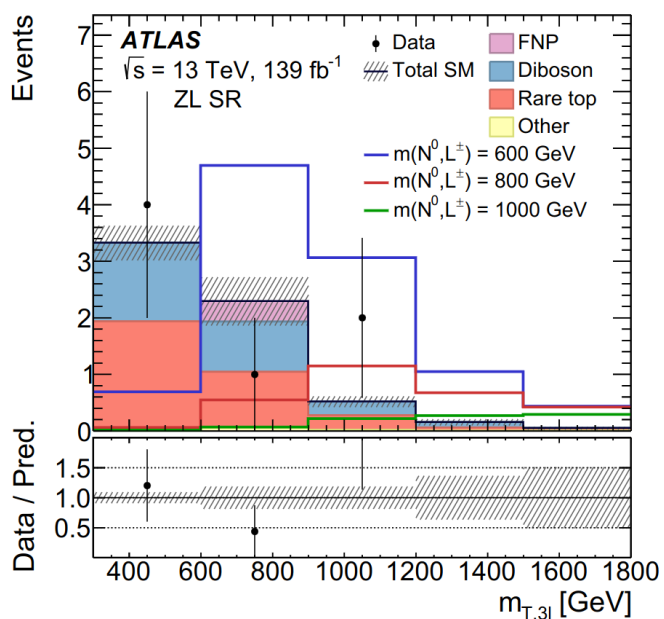
Signal region selection

3 leptons

- Separation by signal event topology
 - Triplet decay into leptonic Z
 - $m_{LL}(OSSF) = [80, 100) \text{ GeV}$, 2 jets
 - No triplet decay into leptonic Z
 - $m_{LL}(OSSF) > 150 \text{ GeV}$, 2 jets
- No jets

4 leptons

- Relatively low SM background
- Separation by two possible lepton charge configurations
 - $|\text{Total charge}| = 0$
 - $|\text{Total charge}| = 2$

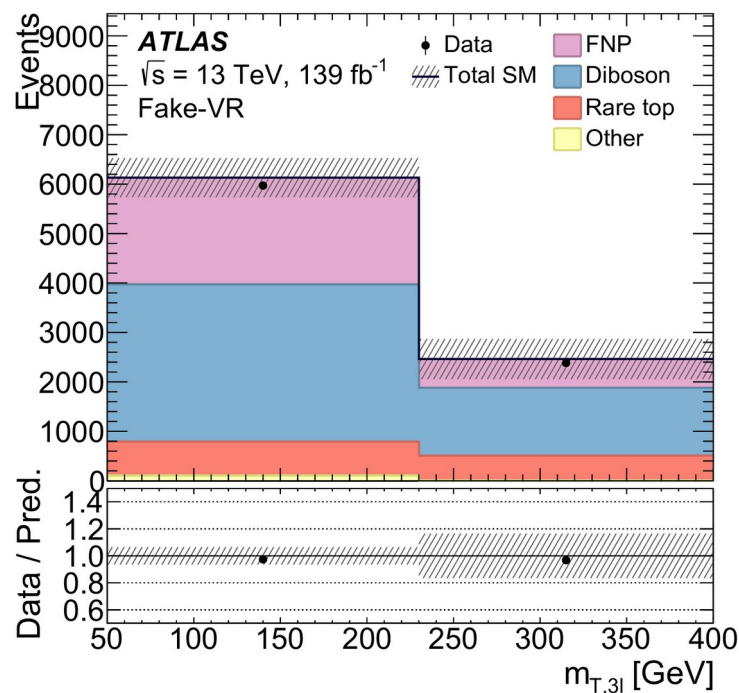
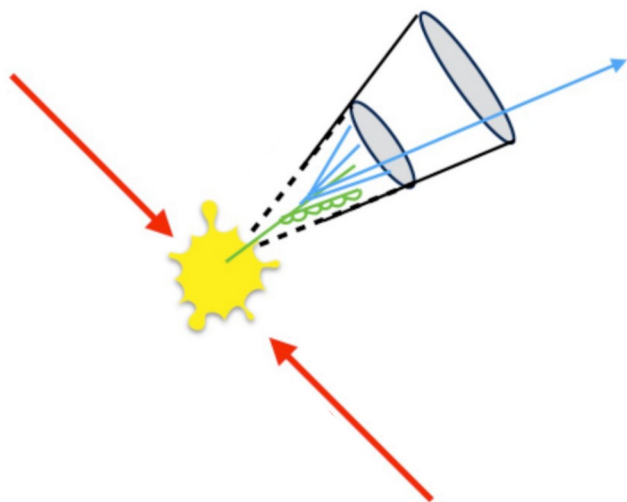


Complete region definitions in backup



Background estimation

- Significant source of background from misreconstructed objects – reducible background
 - Misreconstructed sign of lepton charge (**charge flip**)
 - Incorrectly reconstructed jets, non-prompt leptons from meson decay within jets and electron-photon conversions (**fakes**)
- Usually modeled relatively poorly in MC → **data-driven approaches**





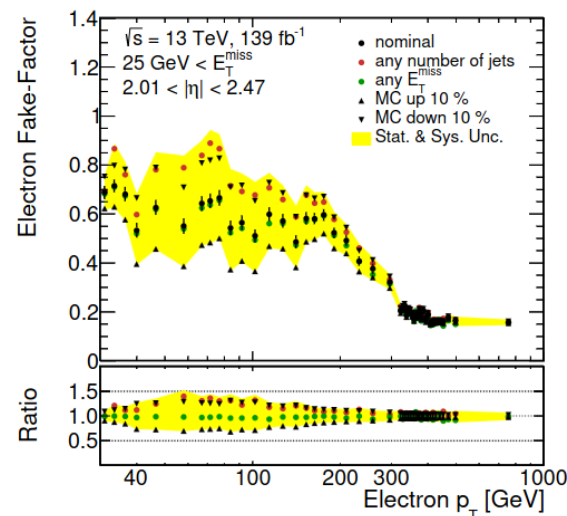
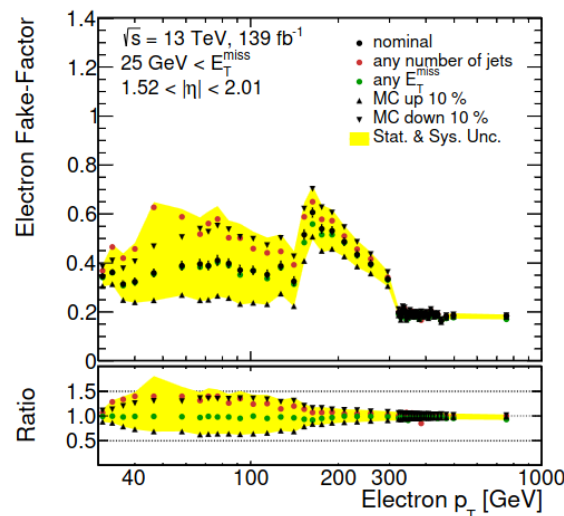
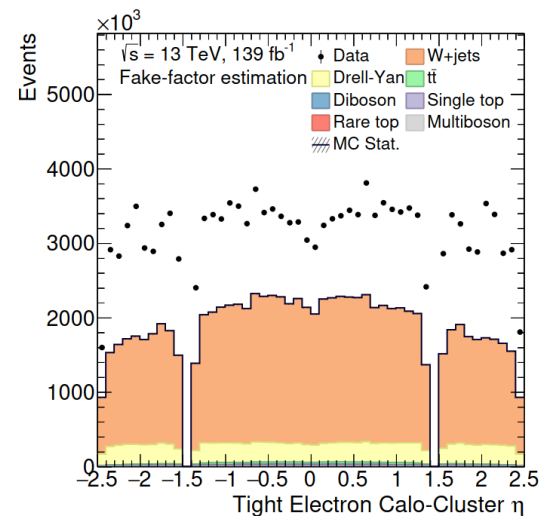
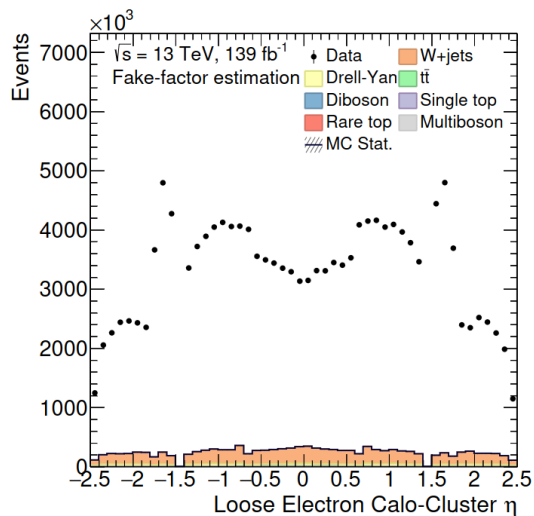
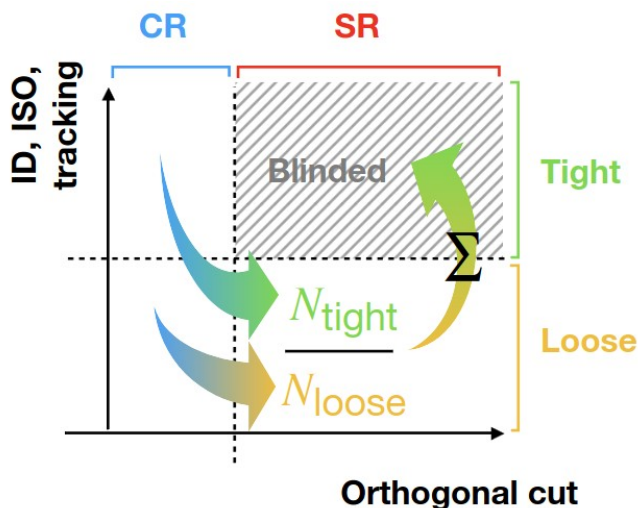
Fake factor method

JINST 18 T11004 (2023)

- Based on exploiting the transfer rate of fake leptons from a looser selection into the signal region's selection
- Transfer rate (fake factor) evaluated on data in orthogonal region rich in fake leptons

$$F = \frac{N_{\text{tight}}^{\text{fake}}}{N_{\text{strictly-loose}}^{\text{fake}}}$$

- Obtained fake factors extrapolated to signal region to obtain background contribution
- Usually binned over p_T and η
- Uncertainties from MC normalization, MC modeling and fakes composition differences between fake-enriched region and SR



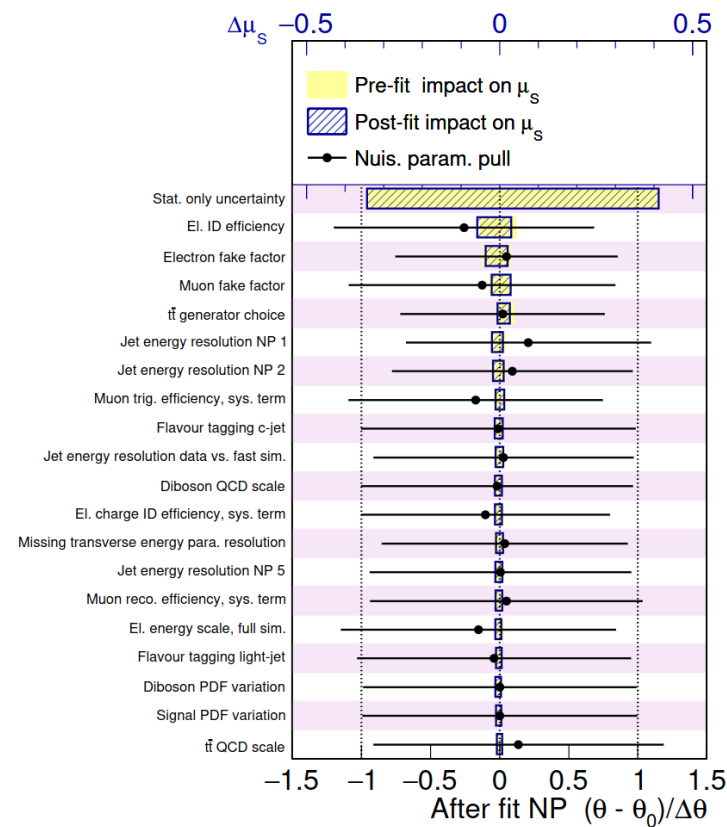
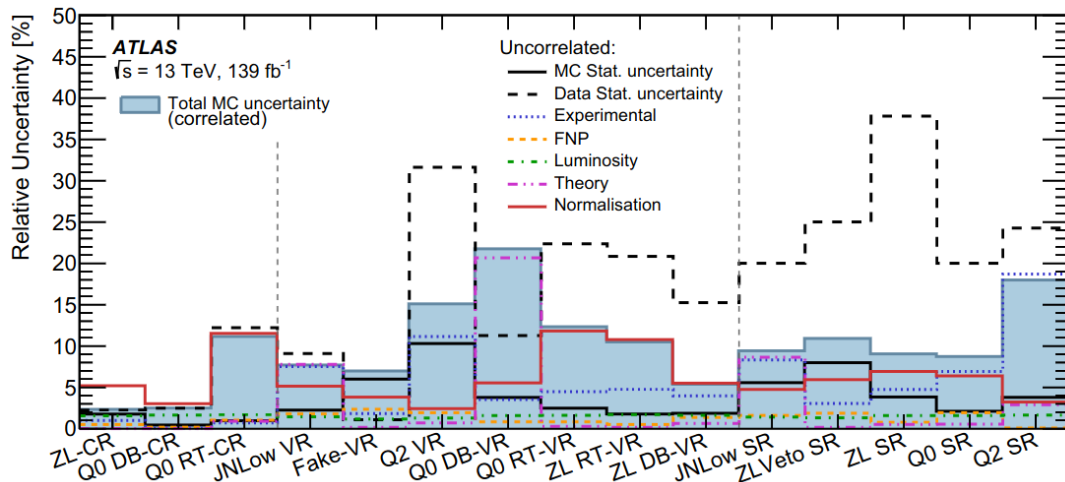
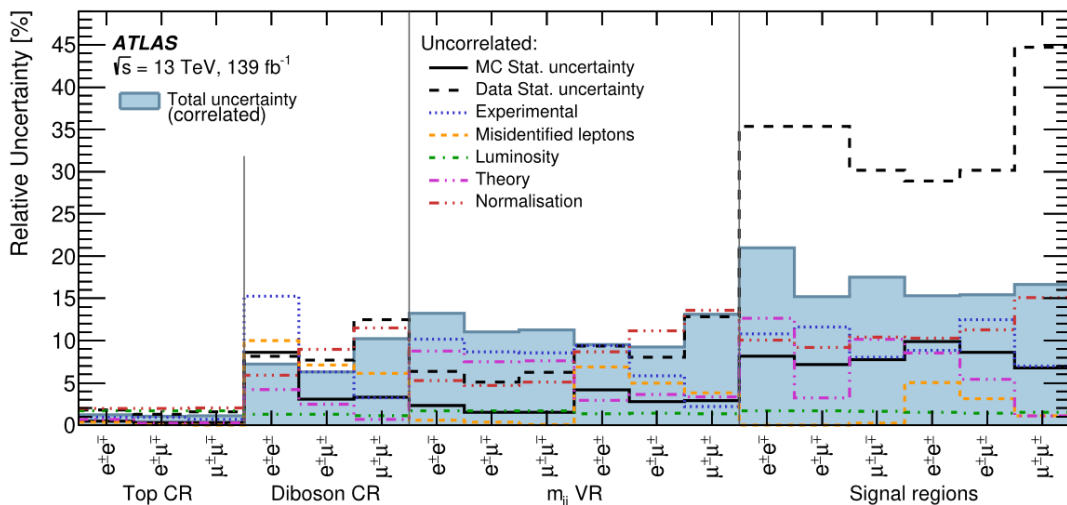
$$2 \text{ lepton case: } N_{TT}^{\text{fakes}} = \left[\sum_{TL} F_2 + \sum_{LT} F_1 - \sum_{LL} F_1 F_2 \right]_{\text{data}} - \left[\sum_{TL} F_2 + \sum_{LT} F_1 - \sum_{LL} F_1 F_2 \right]_{\text{prompt simulation}}$$

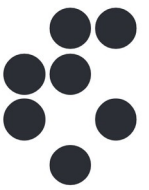
More on this in next talk by Lara



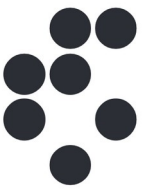
Main sources of uncertainty

- Main source of uncertainty is statistical unc. in data
- ~ 5 % on electron and muon fake factors





How do we improve this?



Strategies for improving analysis sensitivity

Plans to improve the current results with new set of analyses covering type-II and type-III seesaw

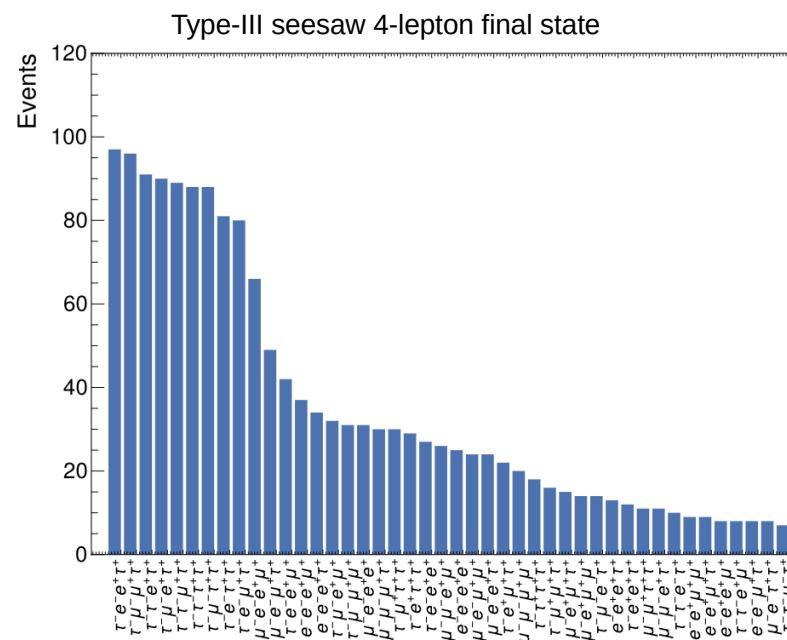
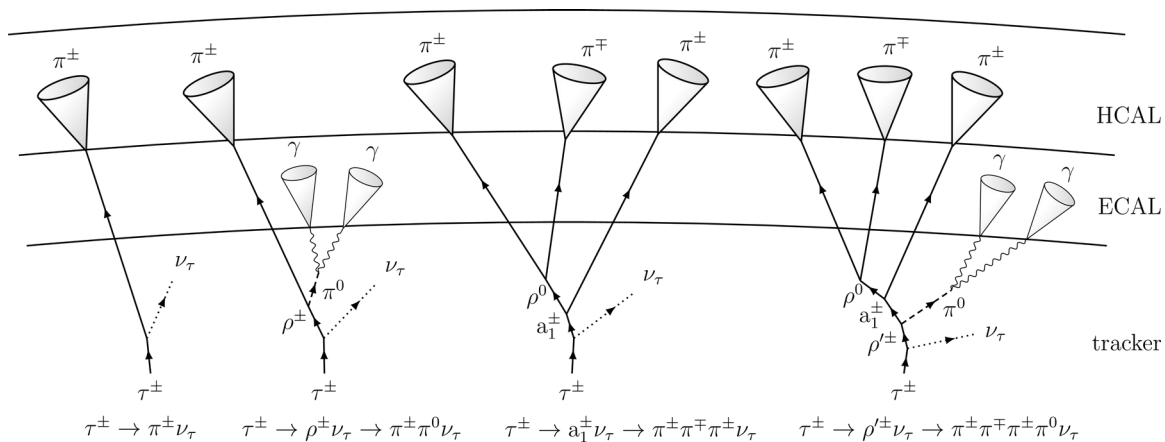
- Higher statistics from **Run 3** – $140 \text{ fb}^{-1} \rightarrow 450 \text{ fb}^{-1}$
- Consider more final states:
 - Include **hadronic tau decays**
 - Type-III: Possibly extend final state to up to 6 leptons
- Utilizing **machine learning approaches** for several aspects in the analysis
 - Signal-background separation (classification)
 - Background estimation - modeling the contribution of fakes



Hadronic tau decays

$$\text{Br}(\tau \rightarrow \text{had}) \sim 65 \%$$

- Significant gain in additional final states
 - Most frequent 2-, 3- and 4-lepton final states **contain taus!**
- Detector signature mimics jets
 - 1- or 3-prong decays
- Reconstruction:
 - Seeded from jets ($|\eta| < 2.5$ coverage) \rightarrow track reco \rightarrow identification \rightarrow electron veto

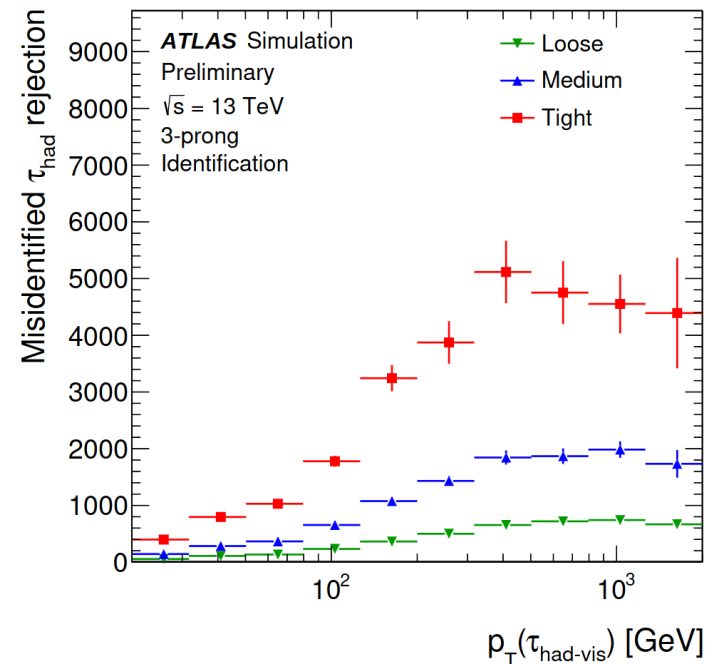
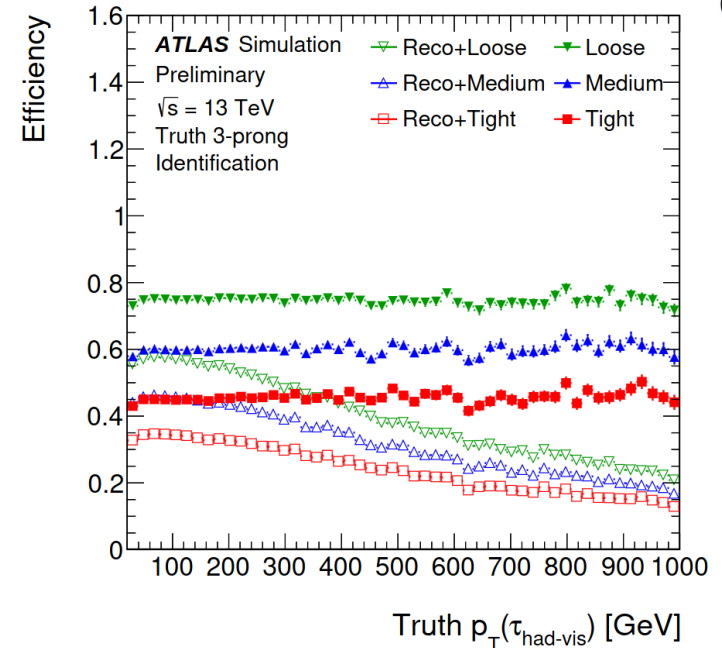
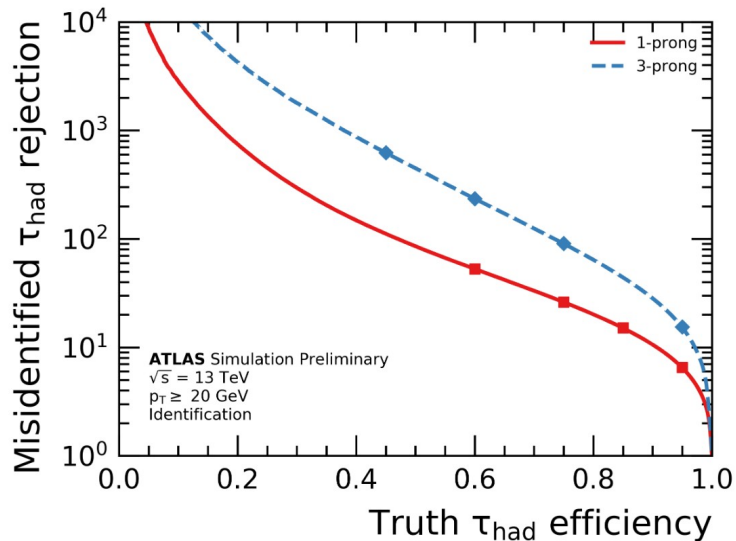


Hadronic tau decays

ATL-PHYS-PUB-2022-044



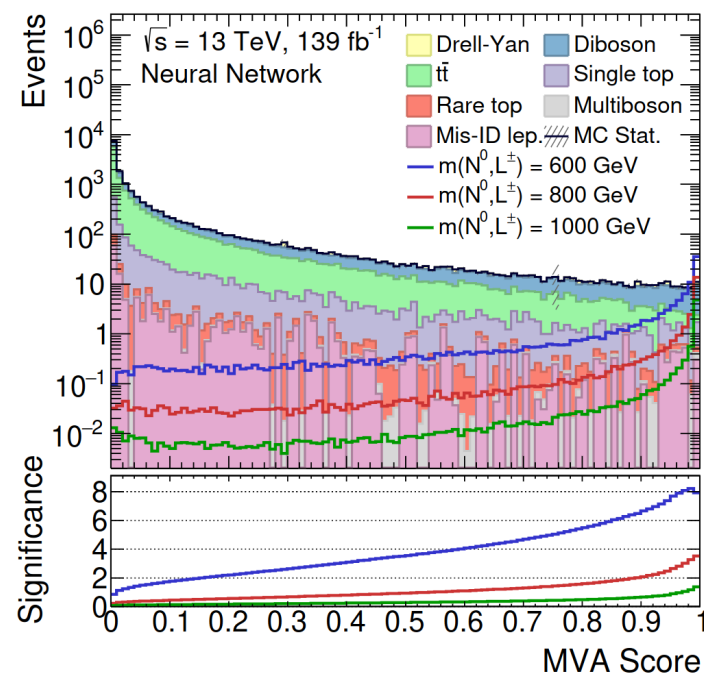
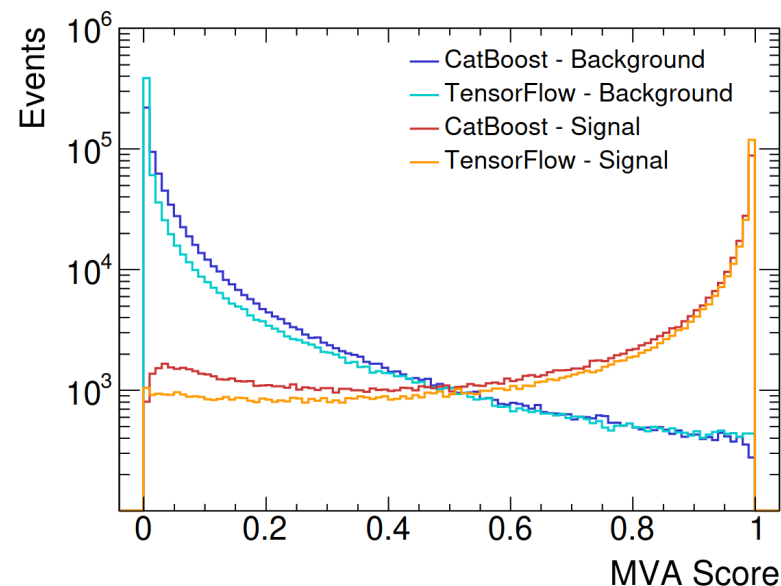
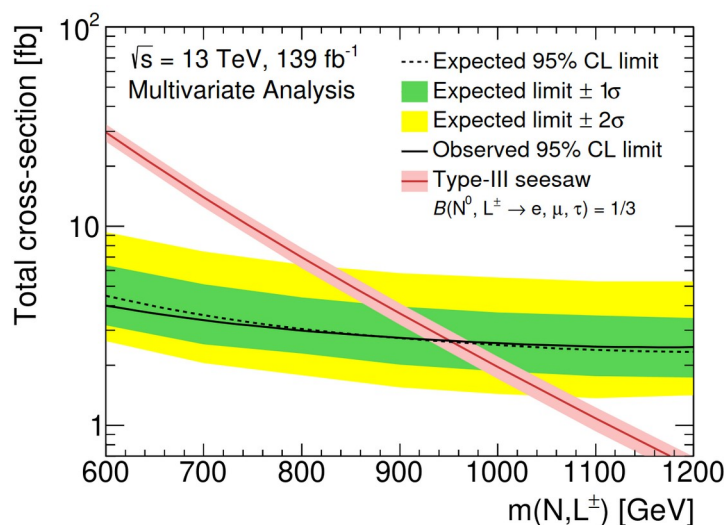
- Recent improvements for Run 3 and reprocessing of Run 2
 - RNN-based track reconstruction and identification
 - Replaces old BTD algorithms → Large performance improvements (e.g. 75-100 % larger rejection at fixed ID efficiency)
- Significant background from misidentified electrons → electron veto (also RNN, factor 3 improved rejection)





Machine learning approaches

- Promising study already done for type-III seesaw in 2-lepton final state
- Loose preselection as input to **binary event classification** into signal/background with NN
- Analysis regions defined on cut of NN score
- Lower limit for triplet mass already increased from 790 GeV to **950 GeV!**





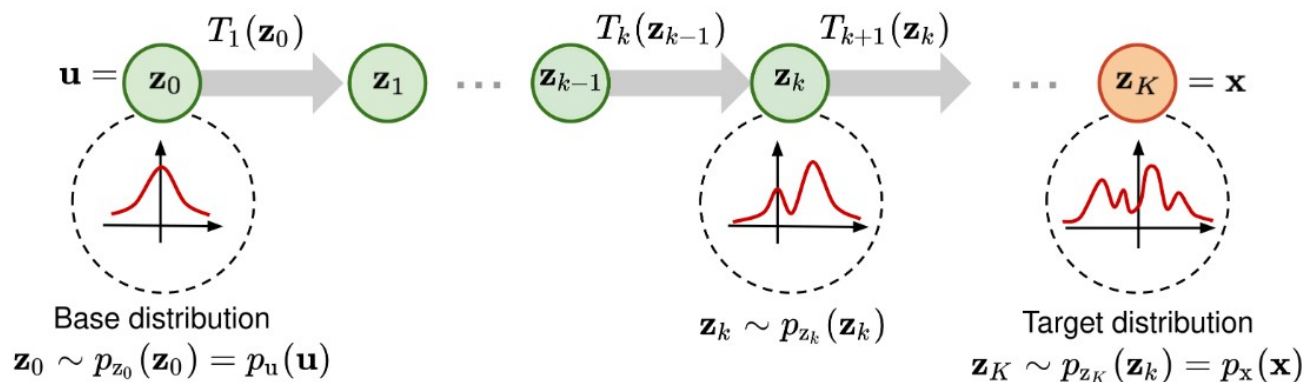
Machine learning approaches

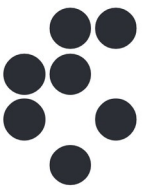
- Plans to use ML in several aspects within the new analyses
 - Improved binary **signal/background classification**
 - Improve **modeling of fakes** background
 - Pure fakes sample required → Need a way to remove prompt contamination
 - Employ generative models to enable infinite sampling of background to improve MC statistics
 - Also intended for reducing uncertainty on fakes contribution
 - Viability study of using normalizing flows [arXiv:2310.08994](https://arxiv.org/abs/2310.08994) [hep-ph]

$$F = \frac{N_{\text{tight}}^{\text{fake}}}{N_{\text{strictly-loose}}^{\text{fake}}}$$

$$r(x) = \frac{P(x)}{Q(x)} = \frac{p(y = 1|x)}{1 - p(y = 1|x)}$$

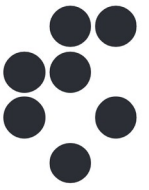
↑
Binary classifier output
gives density ratio directly!





Conclusions

- Current limits on mass from ATLAS Run 2 analyses at 1080 GeV for DCH and 910 GeV for type-III seesaw
 - Analyses done with a cut-based approach
 - Mainly limited by statistical uncertainty in data
- New analyses focusing on type-II and type-III seesaw ongoing
 - Using Run 2 + Run 3 data
 - Including hadronic tau decays
 - Employing advanced machine learning approaches for signal/background separation, to better model fakes background and improve MC statistics



Thank you!



Backup



2-lepton analysis regions

	OS ($\ell^+\ell^- = e^+e^-, e^\pm\mu^\mp, \mu^+\mu^-$)			SS ($\ell^\pm\ell^\pm = e^\pm e^\pm, e^\pm\mu^\pm, \mu^\pm\mu^\pm$)		
	Top CR	m_{jj} VR	SR	Diboson CR	m_{jj} VR	SR
$N(\text{jet})$	≥ 2	≥ 2	≥ 2	≥ 2	≥ 2	≥ 2
$N(b\text{-jet})$	≥ 2	0	0	0	0	0
m_{jj} (GeV)	(60, 100)	$(35, 60) \cup (100, 125)$	(60, 100)	$(0, 60) \cup (100, 300)$	$(0, 60) \cup (100, 300)$	(60, 100)
$m_{\ell\ell}$ (GeV)	≥ 110	≥ 110	≥ 110	≥ 100	≥ 100	≥ 100
$\mathcal{S}(E_T^{\text{miss}})$	≥ 5	≥ 10	≥ 10	≥ 5	≥ 5	≥ 7.5
$\Delta\phi(E_T^{\text{miss}}, \ell)_{\min}$	-	-	≥ 1	-	-	-
$p_T(jj)$ (GeV)	-	-	≥ 100	-	-	≥ 60
$p_T(\ell\ell)$ (GeV)	-	-	≥ 100	-	-	≥ 100
$H_T + E_T^{\text{miss}}$ (GeV)	≥ 300	≥ 300	≥ 300	(300, 500)	≥ 500	≥ 300



3-lepton analysis regions

		ZL				ZLveto	JNLow	
	Fake-VR	CR	DB-VR	RT-VR	SR	SR	VR	SR
		$p_T(\ell_1) > 40 \text{ GeV}$ $p_T(\ell_2) > 40 \text{ GeV}$ $p_T(\ell_3) > 15 \text{ GeV}$						
$S(E_T^{\text{miss}})$	< 5	≥ 5						
$N(\text{jet})$	-	≥ 2					≤ 1	
$N(b\text{-jet})$	-	-	0	≥ 1	-	-	-	-
$m_{\ell\ell}$ (OSSF) [GeV]	-	80–100				≥ 115	≥ 80	
$H_T + E_T^{\text{miss}}$ [GeV]	-	-	-	-	-	≥ 600	-	-
$m_{\ell\ell\ell}$ [GeV]	-	-	≥ 300			≥ 300	-	-
$H_T(\text{SS})$ [GeV]	-	-	-	-	-	≥ 300	-	-
m_{jj} [GeV]	-	-	-	-	-	< 300	-	-
$H_T(\ell\ell\ell)$ [GeV]	-	-	-	-	-	-	≥ 230	
$m_T(\ell_1)$ [GeV]	-	-	≥ 200			-	< 240	≥ 240
$m_T(\ell_2)$ [GeV]	-	< 200	≥ 200			-	≥ 150	
$\Delta R(\ell_1, \ell_2)$	-	-	< 1.2		1.2–3.5	-	≥ 1.3	

$$m_T^{\text{lep}} = \left| \sum_i^{\text{lep}} \vec{P}_i(p_T, 0, \phi, E) + \vec{E}_T^{\text{miss}} \right|$$

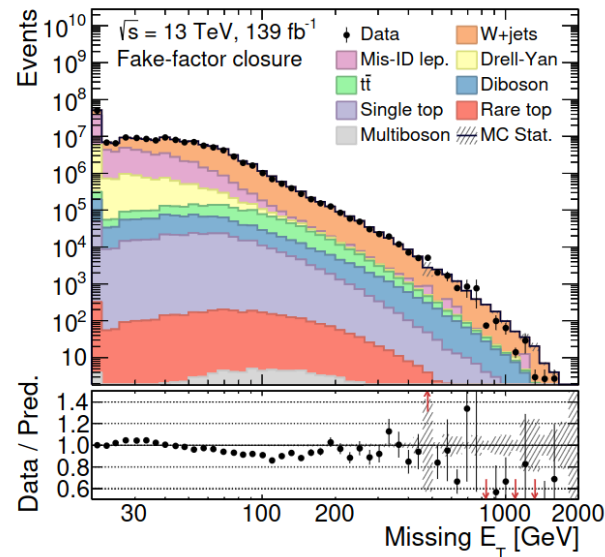
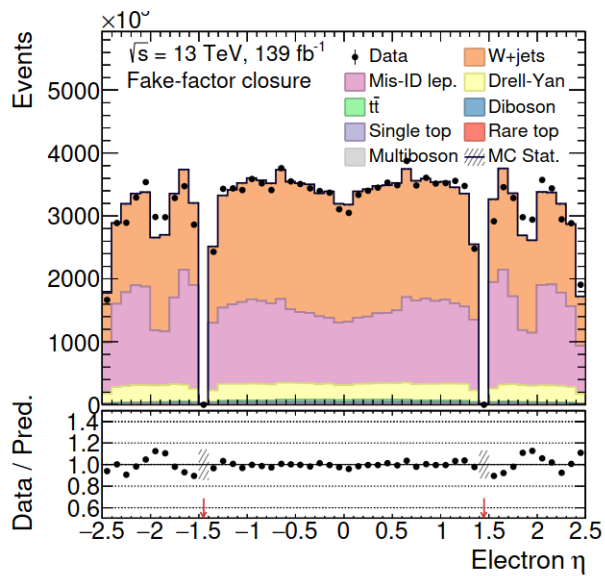
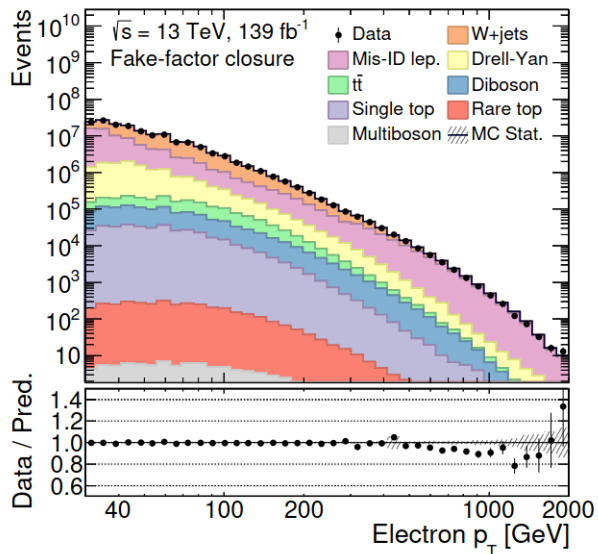
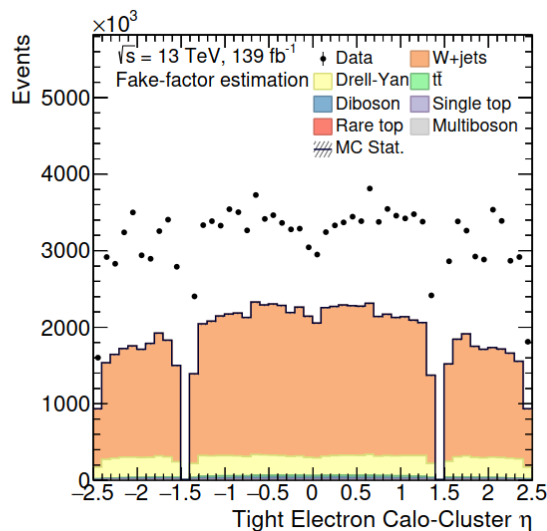
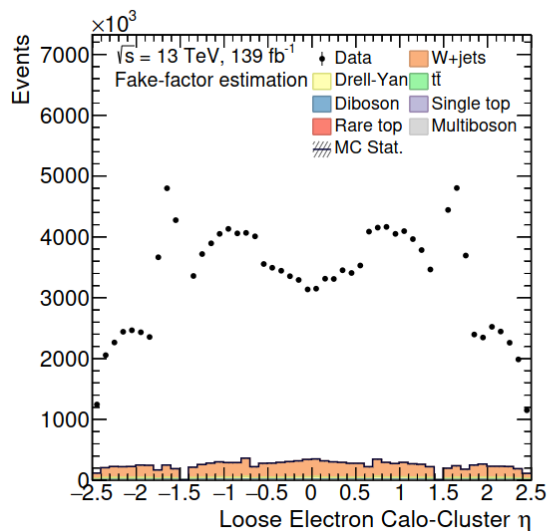


4-lepton analysis regions

	Q0					Q2	
	DB-CR	RT-CR	DB-VR	RT-VR	SR	VR	SR
	$p_T(\ell_{1,2}) > 40 \text{ GeV}$ $p_T(\ell_3) > 15 \text{ GeV}$ $p_T(\ell_4) > 10 \text{ GeV}$						
$ \sum q_e $	0					2	
$N(b\text{-jet})$	0	≥ 2	1	1	0	-	-
$m_{\ell\ell\ell\ell} \text{ [GeV]}$	170–300	< 500	170–300	300–500	≥ 300	< 200 OR < 300	≥ 300
$H_T + E_T^{\text{miss}} \text{ [GeV]}$	-	-	-	≥ 400	≥ 300		≥ 300
N_Z	-	-	-	-	≤ 1	-	-
$S(E_T^{\text{miss}})$	-	-	-	≥ 5	≥ 5	-	-



Fake factor method





Tau performance

